

# Search Notes



Application/Control No.

10/560,494

Examiner

Patrick J. Lee

Applicant(s)/Patent under  
Reexamination

SCHREY ET AL.

Art Unit

2878

## SEARCHED

Class	Subclass	Date	Examiner
250	214.1, 214R, 208.1	5/10/2007 5/21/2007 6/19/2007 6/20/2007	PL
348	294, 392	↓	PL

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East (see attached) - USPAT, US-PGPUB, EPO, JPO, DERWENT	5/10/2007	PL
East (see attached) - USPAT, US-PGPUB, EPO, JPO, DERWENT	5/21/2007	PL
East (see attached) - USPAT, US-PGPUB, EPO, JPO, DERWENT	6/19/2007	PL
East (see attached) - USPAT, US-PGPUB, EPO, JPO, DERWENT	6/20/2007	PL